N-channel TrenchMOS logic level FET 5 October 2012

**Product data sheet** 

## 1. Product profile

### 1.1 General description

Logic level N-channel MOSFET in a SOT404 package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

### **1.2 Features and benefits**

- AEC Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with Vgst(th) rating of greater than 0.5V at 175 °C

### 1.3 Applications

- 12V, 24V and 48V Automotive systems
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

### 1.4 Quick reference data

Table 1. Qui	ick reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	100	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 5 V; T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	-	100	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	-	263	W
Static charact	teristics	· · · · · · · · · · · · · · · · · · ·		1			
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>		-	7.49	9.3	mΩ
Dynamic characteristics							
Q <sub>GD</sub>	gate-drain charge	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; V <sub>DS</sub> = 80 V; Fig. 13; Fig. 14		-	34	-	nC





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## 2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D
2	D	drain		
3	S	source		G-UT4
mb	D	mounting base; connected to drain	D2PAK (SOT404)	mbb076 S

## 3. Ordering information

Table 3. Ordering information							
Type number	Package						
	Name	Description	Version				
BUK969R3-100E	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404				

## 4. Marking

Table 4.   Marking codes	
Type number	Marking code
BUK969R3-100E	BUK969R3-100E

## 5. Limiting values

#### Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Мах	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	100	V
V <sub>DGR</sub>	drain-gate voltage	R <sub>GS</sub> = 20 kΩ		-	100	V
V <sub>GS</sub>	gate-source voltage	T <sub>j</sub> ≤ 175 °C; DC		-10	10	V
		$T_j \le 175 \text{ °C}; \text{ Pulsed}$	[1][2]	-15	15	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 5 V; <u>Fig. 1</u>		-	100	А
		T <sub>mb</sub> = 100 °C; V <sub>GS</sub> = 5 V; <u>Fig. 1</u>		-	71	А
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \ \mu$ s; Fig. 4		-	405	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	263	W
T <sub>stg</sub>	storage temperature			-55	175	°C
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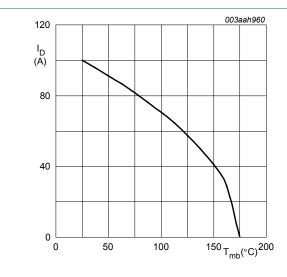
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Symbol	Parameter	Conditions		Min	Мах	Unit
Tj	junction temperature			-55	175	°C
Source-drai	in diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C		-	100	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^\circ C$		-	405	А
Avalanche i	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\label{eq:ID} \begin{split} I_D &= 100 \text{ A};  \text{V}_{\text{sup}} \leq 100 \text{ V};  \text{R}_{\text{GS}} = 50  \Omega; \\ \text{V}_{\text{GS}} &= 5 \text{ V};  \text{T}_{\text{j(init)}} = 25 ^{\circ}\text{C}; \text{ unclamped}; \\ \hline \text{Fig. } 3 \end{split}$	[3][4]	-	219	mJ

- Accumulated pulse duration up to 50 hours delivers zero defect ppm [1]
- [2] Significantly longer life times are achieved by lowering  $T_i$  and or  $V_{GS}$

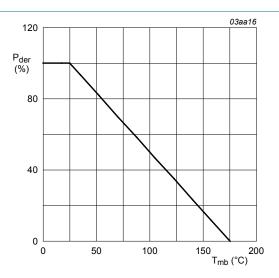
Single-pulse avalanche rating limited by maximum junction temperature of 175 °C. Refer to application note AN10273 for further information.

[3] [4]



Continuous drain current as a function of Fig. 1. mounting base temperature

 $V_{GS} \ge 5V$ 

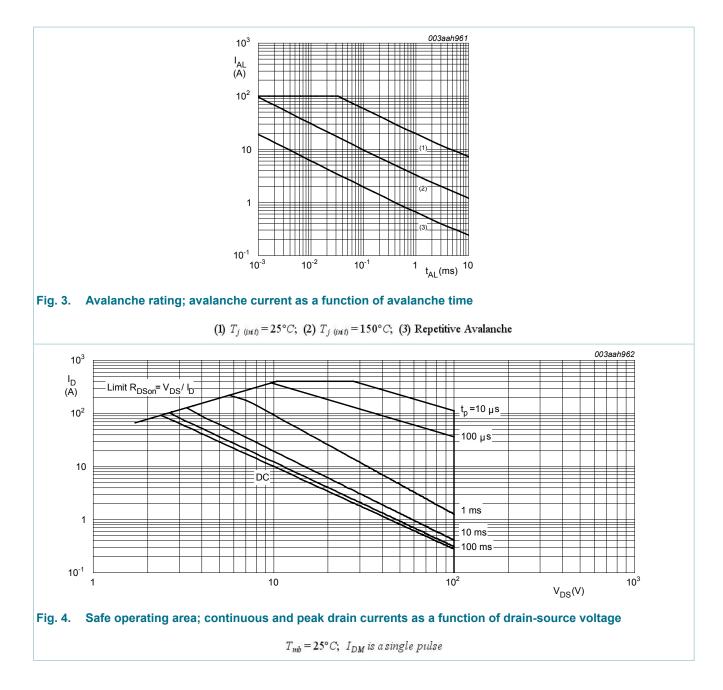




$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

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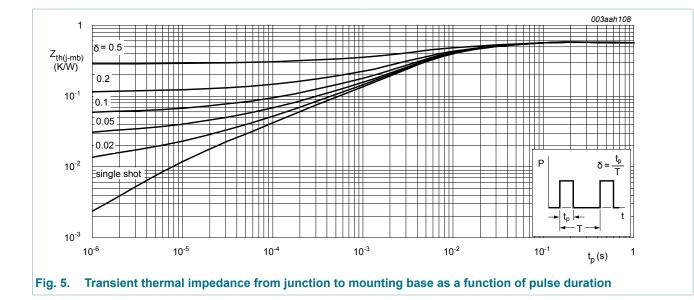


### 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 5	-	-	0.57	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	minimum footprint ; mounted on a printed-circuit board	-	50	-	K/W

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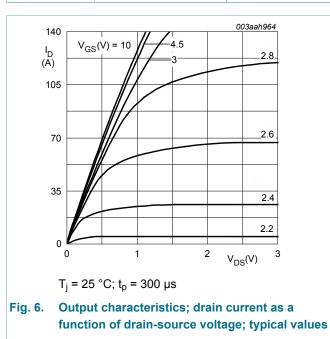


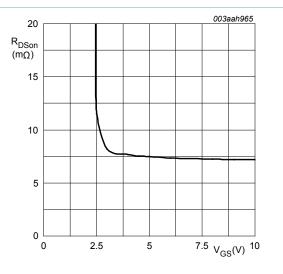
#### **Characteristics** 7.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	octeristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = 25 °C	100	-	-	V
	breakdown voltage	$e = \begin{cases} I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & 100 \\ I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}\text{C} & 90 \\ \end{cases}$ hold $I_D = 1 \ \text{mA}; \ V_{DS} = V_{GS}; \ T_j = 25 \ ^{\circ}\text{C}; & 1.4 \\ \hline Fig. \ 9; \ Fig. \ 10 \\ I_D = 1 \ \text{mA}; \ V_{DS} = V_{GS}; \ T_j = -55 \ ^{\circ}\text{C}; & -\frac{1}{Fig. \ 9} \\ \hline I_D = 1 \ \text{mA}; \ V_{DS} = V_{GS}; \ T_j = 175 \ ^{\circ}\text{C}; & 0.5 \\ \hline Fig. \ 9 \\ \hline I_D = 1 \ \text{mA}; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{DS}} \\ \hline V_{DS} = 100 \ V; \ V_{GS} = 0 \ V; \ T_j = 175 \ ^{\circ}\text{C} & -\frac{1}{V_{OS}} \\ \hline V_{GS} = 100 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{GS}} \\ \hline V_{GS} = -10 \ V; \ V_{SS} = 0 \ V; \ T_{S} = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{S}} \\ \hline V_{SS} = -10 \ V; \ V_{SS} = 0 \ V; \ T_{S} = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{S}} \\ \hline V_{SS} = -10 \ V; \ V_{SS} = 0 \ V; \ T_{S} = 25 \ ^{\circ}\text{C} & -\frac{1}{V_{S}} \\ \hline V_{SS} = -10 \ V; \ V_{SS} = 0 \ V; \ T_{S} = 0 \ V; \ T_{S} = 0 \ V; \ T_$	-	-	V	
00()	gate-source threshold voltage	5 50 60 ,	1.4	1.7	2.1	V
		,	-	-	2.45	V
		,	0.5	-	-	V
I <sub>DSS</sub> drain leakage curre	drain leakage current	$V_{DS}$ = 100 V; $V_{GS}$ = 0 V; $T_j$ = 25 °C	-	0.06	1	μA
			$V_{DS}$ = 100 V; $V_{GS}$ = 0 V; $T_j$ = 175 °C	-	-	500
I <sub>GSS</sub>	gate leakage current	$V_{GS}$ = 10 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
		V <sub>GS</sub> = -10 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	7.49	9.3	mΩ
	resistance		-	7.23	8.9	mΩ
		V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C; Fig. 12; Fig. 11	-	-	25.7	mΩ
Dynamic ch	aracteristics	· · · · · ·	I			
Q <sub>G(tot)</sub>	total gate charge	$I_D$ = 25 A; $V_{DS}$ = 80 V; $V_{GS}$ = 5 V;	-	94.3	-	nC
Q <sub>GS</sub>	gate-source charge	Fig. 13; Fig. 14	-	15.2	-	nC

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Q <sub>GD</sub>	gate-drain charge		-	34	-	nC
C <sub>iss</sub>	input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz;	-	8739	11650	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; <u>Fig. 15</u>	-	499	599	pF
C <sub>rss</sub>	reverse transfer capacitance		-	312	427	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 80 V; R <sub>L</sub> = 3.2 Ω; V <sub>GS</sub> = 5 V; R <sub>G(ext)</sub> = 5 Ω	-	39.5	-	ns
t <sub>r</sub>	rise time		-	95.1	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	118	-	ns
t <sub>f</sub>	fall time		-	93.4	-	ns
L <sub>D</sub>	internal drain inductance	from upper edge of drain mounting base to center of die	-	2.5	-	nH
L <sub>S</sub>	internal source inductance	from source lead to source bonding pad	-	7.5	-	nH
Source-dra	in diode	·				
V <sub>SD</sub>	source-drain voltage	$I_{S}$ = 25 A; $V_{GS}$ = 0 V; $T_{j}$ = 25 °C; <u>Fig. 16</u>	-	0.8	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S}$ = 20 A; dI <sub>S</sub> /dt = -100 A/µs; V <sub>GS</sub> = 0 V;	-	55.5	-	ns
Qr	recovered charge	V <sub>DS</sub> = 25 V	-	142	-	nC



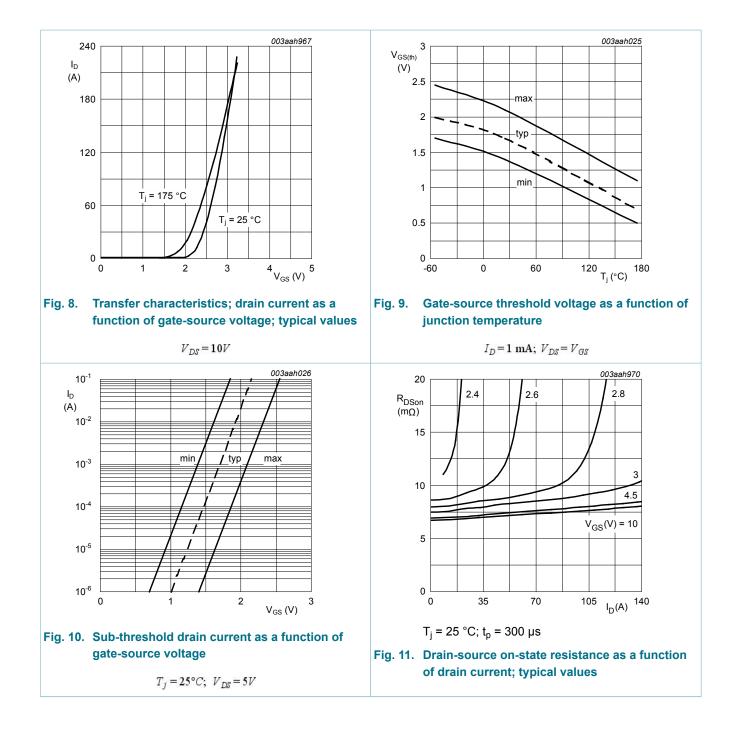




 $T_j = 25^{\circ}C; \ I_D = 25A$ 

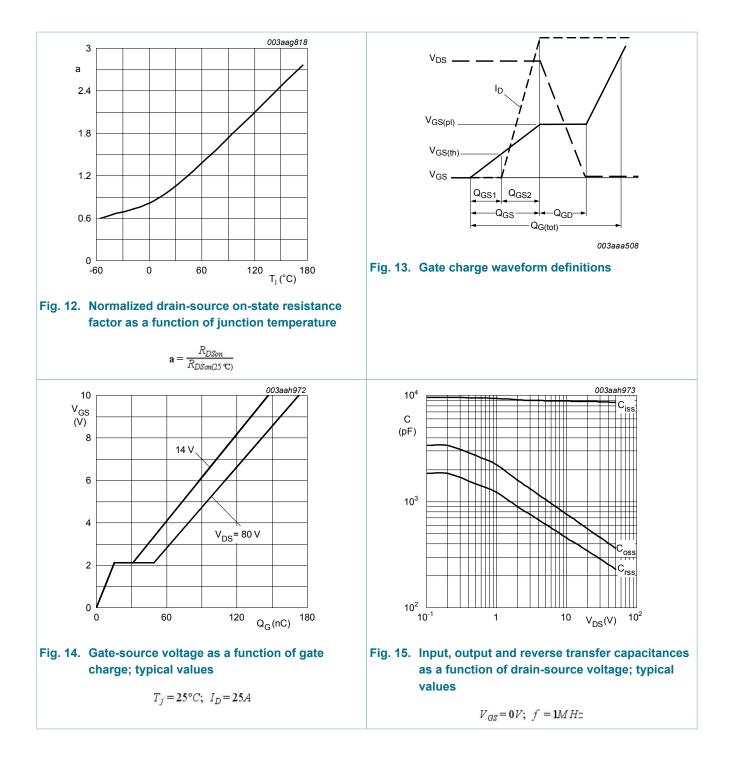
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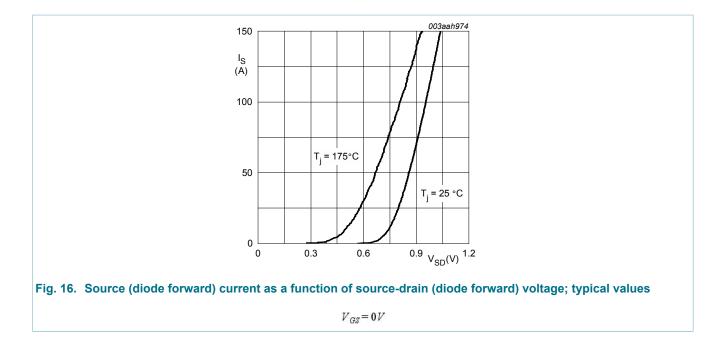
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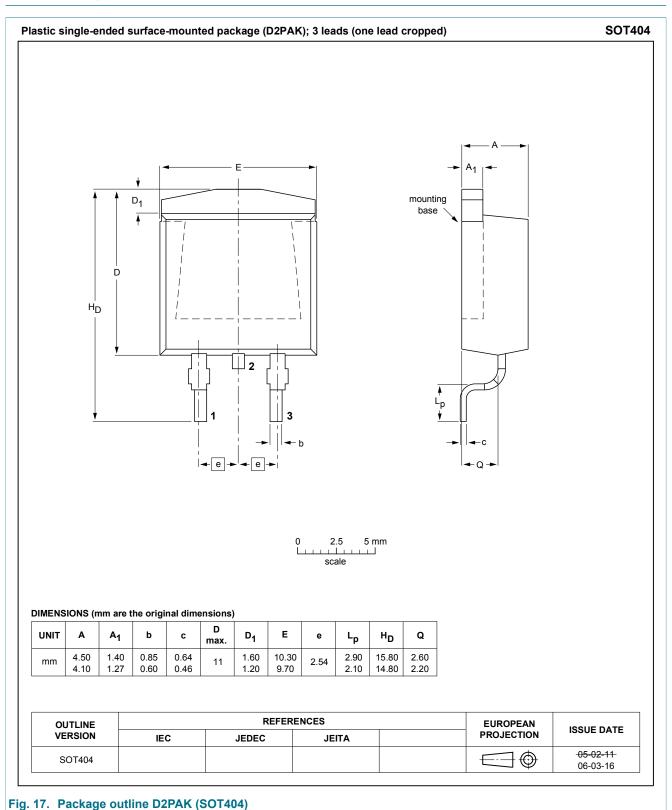
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### 8. Package outline



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### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status [ <u>3]</u>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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